

# Scanning Electron Microscopy

1979

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# SCANNING ELECTRON MICROSCOPY/1979/II

An  
INTERNATIONAL REVIEW  
of  
ADVANCES  
in  
TECHNIQUES AND APPLICATIONS  
of the  
SCANNING ELECTRON MICROSCOPE  
PART II

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For this publication the volume number and the year are the same. Individual papers should be referred to by the year and the part, (Roman Numeral included after the year). Thus, SEM/1979 has three parts: I, II, and III; and SEM/1978 had two parts: I and II.

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## EXPLANATION OF THE TYPE OF PAPERS IN THIS VOLUME:\*

### TUTORIAL

Presentation of established material in teaching lecture type format with emphasis on techniques and "how to do it".

### REVIEW

A review of the chosen subject with emphasis on author's own work, placing it in context with relevant literature, and putting the topic in perspective.

\* For identification of these papers see Table of Contents or Major Subject Index.

Most of the papers included in this volume were presented at the Scanning Electron Microscopy/1979 meetings, held April 16-20, 1979, at Sheraton Park Hotel, Washington, D.C.. The program for various parts of the meeting was prepared and conducted by the advisors listed above. Om Johari was the director of the meetings.

The division of papers in three parts of the Scanning Electron Microscopy/1979 volume is somewhat arbitrary. In general, the editors attempted to follow the scheme given below. We realize that such a scheme is not satisfactory in all cases; thus biological microanalysis papers are placed in part II because of the increasing interaction between physical and biological scientists in that field. Similarly, many papers under mineralized tissue originated from geology departments, and so we elected to place them in part II.

- |          |  |
|----------|--|
| Part I   | Papers primarily of interest to physical scientists.                                   |
| Part III | Papers primarily of interest to biological scientists.                                 |
| Part II  | Remaining papers, presumably of interest to both - physical and biological scientists. |

A major subject index has been included in parts II and III.

Additionally, a major subject index of SEM/1978/I and SEM/1978/II has been included in SEM/1979/II and SEM/1979/III respectively.

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### ► SCANNING ELECTRON MICROSCOPY/1980

April, 21-25, 1980 --- CHICAGO, ILLINOIS

The planning for SEM/1980 has already started. Your suggestions for review and tutorial papers, and workshop topics are earnestly requested; please forward them at the earliest to Om Johari. The tentative outline of important dates is as follows:

CALL FOR PAPERS ISSUED:	Sept. 1, 1979
Abstracts Due	Nov. 1, 1979
Program Outline available	Dec. 10, 1979
Manuscripts of accepted abstracts due	Jan. 15, 1980
Meeting Dates	Apr. 21-25, 1980

The meetings will take place at McCormick Inn, 23rd and Lake Shore Drive; Chicago, IL 60616, USA. For room reservations, contact the Inn directly; those in USA may call 800-621-6909. Economy rooms will be available at McCormick Inn's affiliated motels (on a regular bus route from the Inn).

For all information about the meetings contact Om Johari.

### ► MAILING LIST INFORMATION:

Immediately after the SEM/1979 meetings we intend to start computerizing our mailing lists. All those who have registered for the 1979 meetings, or ordered the SEM volume during the last 12 months or wrote to us to get on our lists will be automatically added to the list. Please send name, complete postal address (including zip or other postal codes) and telephone number to Om Johari at the above address. Our lists are organized by zip/postal codes, therefore we cannot add or retain your name on our lists if the zip code information is missing.

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Scanning Electron Microscopy/1978/I	Physical, technical and General interest papers	\$37.00*
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